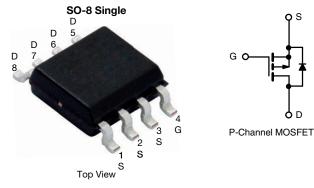


FDS6681Z-NL-VB Datasheet

P-Channel 30 V (D-S) MOSFET

| PRODUCT SUMMARY | | | | | | |
|--|--------|--|--|--|--|--|
| V _{DS} (V) | -30 | | | | | |
| $R_{DS(on)}$ max. (Ω) at V_{GS} = 10 V | 0.0050 | | | | | |
| $R_{DS(on)}$ max. (Ω) at V_{GS} = 4.5 V | 0.0080 | | | | | |
| Q _g typ. (nC) | 27 | | | | | |
| I _D (A) | 18 | | | | | |
| Configuration | Single | | | | | |



FEATURES

- TrenchFET[®] Gen IV p-channel power MOSFET
- Enables higher power density
- 100 % R_g and UIS tested



HALOGEN FREE

APPLICATIONS

- Battery management in mobile devices
- Adapter and charger switch
- · Battery switch
- · Load switch

| PARAMETER | | SYMBOL | LIMIT | UNIT |
|---|------------------------|-----------------------------------|----------------------|------|
| Drain-source voltage | | V _{DS} | -30 | V |
| Gate-source voltage | | V _{GS} | ± 20 | v |
| | T _C = 25 °C | | -18 | |
| Continuous drein surrent (T 150 °C) | T _C = 70 °C | | -13 | |
| Continuous drain current (T _J = 150 °C) | T _A = 25 °C | I _D | -11 | |
| | T _A = 70 °C | | -8 | |
| Pulsed drain current (t = 100 µs) | | I _{DM} | -145 | A |
| Continuous source-drain diode current | T _C = 25 °C | | -5 | |
| | T _A = 25 °C | I _S | -2.8 ^{b, c} | |
| Single pulse avalanche current | | I _{AS} | -25 | |
| Single pulse avalanche energy | L = 0.1 mH | E _{AS} | 31.2 | mJ |
| Maximum power dissipation | T _C = 25 °C | | 5.6 | |
| | T _C = 70 °C | | 3.6 | w |
| | T _A = 25 °C | l _P | 3.1 ^{b, c} | |
| | T _A = 70 °C | | 2 ^{b, c} | |
| Operating junction and storage temperature range | | T _J , T _{stg} | -55 to +150 | *0 |
| Soldering recommendations (peak temperature) ^c | | | 260 | °C |

THERMAL RESISTANCE RATINGS

| PARAMETER | SYMBOL | TYPICAL | MAXIMUM | UNIT | | | |
|----------------------------------|--------------|-------------------|---------|------|-------|--|--|
| Maximum junction-to-ambient b | t ≤ 10 s | R _{thJA} | 34 | 40 | °C/W | | |
| Maximum junction-to-case (drain) | Steady state | R _{thJF} | 18 | 22 | -0/10 | | |

Notes

a. Package limited b. Surface mounted on 1" x 1" FR4 board

b. Surface modified of 1 × 1 FR4 board
c. t = 10 s
d. The SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection
e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components
f. Maximum under steady state conditions is 85 °C/W

g. T_C = 25 °C

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNIT | |
|---|-------------------------|---|------|----------|------|---------|--|
| Static | • | | | <u> </u> | | | |
| Drain-source breakdown voltage | V _{DS} | V _{GS} = 0 V, I _D = -250 μA | -30 | - | - | V | |
| V _{DS} temperature coefficient | $\Delta V_{DS}/T_{J}$ | I _D = -10 mA | | -17 | - | | |
| V _{GS(th)} temperature coefficient | $\Delta V_{GS(th)}/T_J$ | I _D = -250 μA | - | 5.5 | - | mV/°C | |
| Gate-source threshold voltage | V _{GS(th)} | $V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$ | -1 | - | -2.2 | V | |
| Gate-source leakage | I _{GSS} | $V_{DS} = 0 V, V_{GS} = +16 / -20 V$ | - | - | 100 | nA | |
| Zero gate voltage drain current | I _{DSS} | | | - | -1 | | |
| | | $V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 70 ^{\circ}\text{C}$ | - | - | -15 | μA | |
| On-state drain current ^a | I _{D(on)} | $V_{DS} \ge$ -10 V, V_{GS} = -10 V | -40 | - | - | Α | |
| | P | V _{GS} = -10 V, I _D = -15 A | - | 0.0050 | - | Ω | |
| Drain-source on-state resistance ^a | R _{DS(on)} | V _{GS} = -4.5 V, I _D = -10 A | - | 0.0080 | - | | |
| Forward transconductance ^a | 9 _{fs} | V _{DS} = -15 V, I _D = -15 A | - | 81 | - | S | |
| Dynamic ^b | | | | • | • | | |
| Input capacitance | C _{iss} | | - | 3490 | - | pF | |
| Output capacitance | C _{oss} | V _{DS} = -15 V, V _{GS} = 0 V, f = 1 MHz | - | 1420 | - | | |
| Reverse transfer capacitance | C _{rss} | | - | 70 | - | | |
| Total gate charge | Qg | $V_{DS} = -15 \text{ V}, \text{ V}_{GS} = -10 \text{ V}, \text{ I}_{D} = -10 \text{ A}$ | - | 56 | 84 | nC | |
| | | | - | 27 | 41 | | |
| Gate-source charge | Q _{gs} | V _{DS} = -15 V, V _{GS} = -4.5 V, I _D =-10 A | - | 9.4 | - | | |
| Gate-drain charge | Q _{qd} | | - | 8.2 | - | | |
| Gate resistance | R _q | f = 1 MHz | 1.5 | 3.5 | 6 | Ω | |
| Turn-on delay time | t _{d(on)} | | - | 15 | 30 | - | |
| Rise time | t _r | V _{DD} = -15 V, R _L = 1.5 Ω, I _D ≅ -10 A, | - | 6 | 12 | | |
| Turn-off delay time | t _{d(off)} | V_{GEN} = -10 V, R_{g} = 1 Ω | - | 39 | 78 | | |
| Fall time | t _f | | - | 10 | 20 | | |
| Turn-on delay time | t _{d(on)} | | - | 34 | 68 | ns - | |
| Rise time | tr | V _{DD} = -15 V, R _L = 1.5 Ω, I _D ≅ -10 A, | - | 86 | 172 | | |
| Turn-off delay time | t _{d(off)} | $V_{GEN} = -4.5 \text{ V}, \text{ R}_{g} = 1 \Omega$ | - | 31 | 62 | | |
| Fall time | t _f | | - | 22 | 44 | | |
| Drain-Source Body Diode Characteristi | cs | | | <u> </u> | • | | |
| Continuous source-drain diode current | Is | T _C = 25 °C | - | - | -5 | ^ | |
| Pulse diode forward current | I _{SM} | | - | - | -150 | A | |
| Body diode voltage | V _{SD} | I _S = -5 A, V _{GS} = 0 V | - | -0.73 | -1.1 | V | |
| Body diode reverse recovery time | t _{rr} | | - | 44 | 88 | ns | |
| Body diode reverse recovery charge | Q _{rr} | | - | 41 | 82 | nC | |
| Reverse recovery fall time | ta | $I_F = -10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^{\circ}\text{C}$ | | 19 | - | | |
| Reverse recovery rise time | t _b | | - | 25 | - | ns | |

Notes

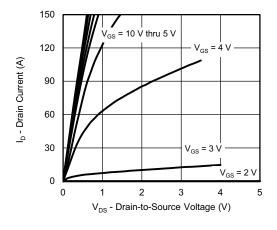
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing

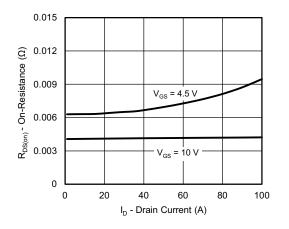
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

semi

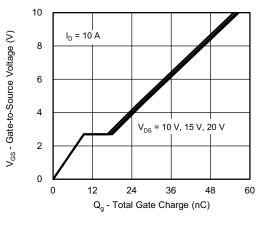




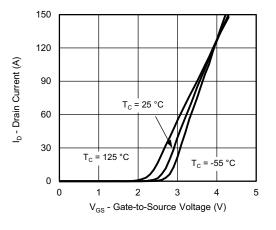
Output Characteristics



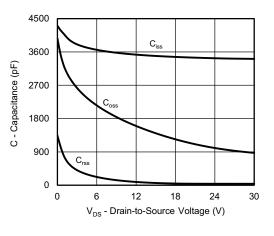
On-Resistance vs. Drain Current and Gate Voltage



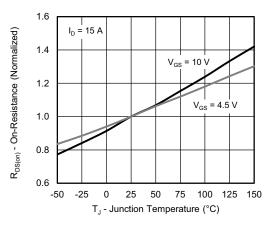
Gate Charge



Transfer Characteristics

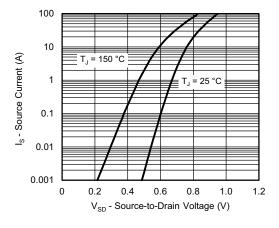


Capacitance

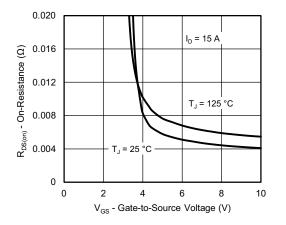


On-Resistance vs. Junction Temperature

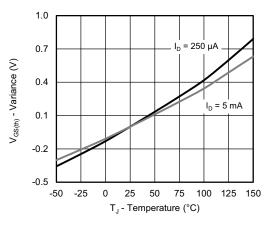




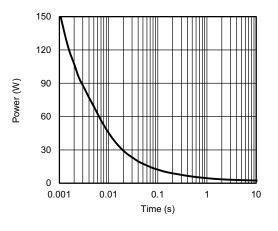
Source-Drain Diode Forward Voltage



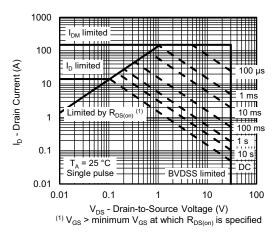
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

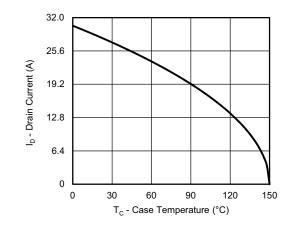


Single Pulse Power, Junction-to-Ambient

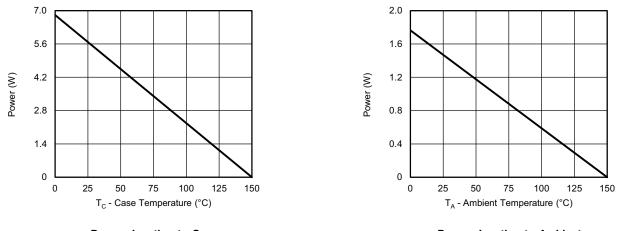


Safe Operating Area, Junction-to-Ambient





Current Derating ^a



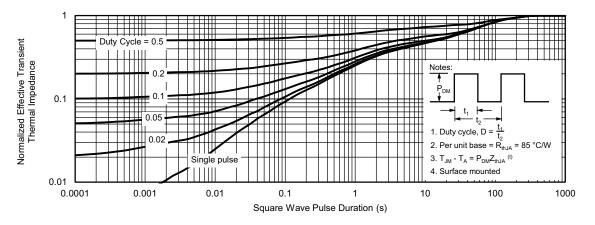
Power, Junction-to-Case

Power, Junction-to-Ambient

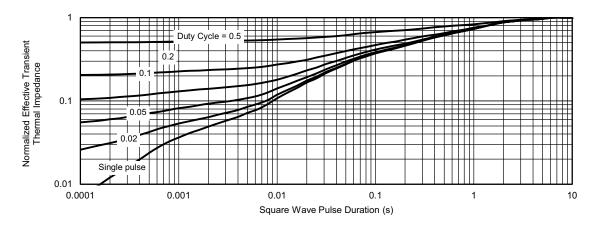
Note

a. The power dissipation P_D is based on T_J max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





Normalized Thermal Transient Impedance, Junction-to-Ambient



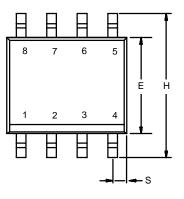
Normalized Thermal Transient Impedance, Junction-to-Case

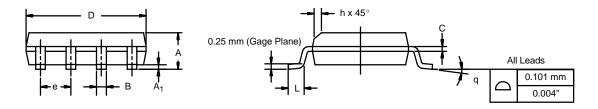




SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

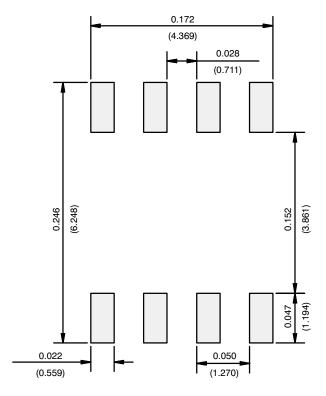




| | MILLIN | IETERS | INCHES | | |
|---|--------|--------|-----------|-------|--|
| DIM | Min | Мах | Min | Max | |
| А | 1.35 | 1.75 | 0.053 | 0.069 | |
| A ₁ | 0.10 | 0.20 | 0.004 | 0.008 | |
| В | 0.35 | 0.51 | 0.014 | 0.020 | |
| С | 0.19 | 0.25 | 0.0075 | 0.010 | |
| D | 4.80 | 5.00 | 0.189 | 0.196 | |
| E | 3.80 | 4.00 | 0.150 | 0.157 | |
| е | 1.27 | BSC | 0.050 BSC | | |
| н | 5.80 | 6.20 | 0.228 | 0.244 | |
| h | 0.25 | 0.50 | 0.010 | 0.020 | |
| L | 0.50 | 0.93 | 0.020 | 0.037 | |
| q | 0° | 8° | 0° | 8° | |
| S | 0.44 | 0.64 | 0.018 | 0.026 | |
| ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498 | | | | | |



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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